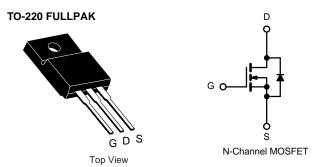


# HY050N08B-VB Datasheet N-Channel 80 V (D-S) MOSFET

PRODU	CT SUMMARY		
V <sub>DS</sub> (V)	$R_{DS(on)}(\Omega)$	I <sub>D</sub> (A)	Q <sub>g</sub> (Typ.)
	0.0064 at V <sub>GS</sub> = 10 V	215 a	
80	0.0070 at V <sub>GS</sub> = 6.0 V	205 <sup>a</sup>	17.1 nC
	0.0087 at V <sub>GS</sub> = 4.5 V	184	



#### **FEATURES**

- Trench Power MOSFET
- 100 % R<sub>g</sub> and UIS Tested

#### **APPLICATIONS**

- Primary Side Switching
- Synchronous Rectification
- DC/AC Inverters
- LED Backlighting



ABSOLUTE MAXIMUM RATINGS (	$T_A = 25  ^{\circ}\text{C}$ , unless	otherwise noted	)		
Parameter		Symbol	Limit	Unit	
Drain-Source Voltage		V <sub>DS</sub>	80	V	
Gate-Source Voltage		V <sub>GS</sub>	± 20	v	
	T <sub>C</sub> = 25 °C		215 <sup>a</sup>		
Ossilia a a Davis Ossia (T. 150.00)	T <sub>C</sub> = 70 °C		205ª		
Continuous Drain Current (T <sub>J</sub> = 150 °C)	T <sub>A</sub> = 25 °C	I <sub>D</sub>	186 <sup>b, c</sup>		
	T <sub>A</sub> = 70 °C		149 b, c		
Pulsed Drain Current (t = 100 μs)		I <sub>DM</sub>	150	A	
Osalis a a Osasa Bais Bisda Osasa	T <sub>C</sub> = 25 °C		75a		
Continuous Source-Drain Diode Current	T <sub>A</sub> = 25 °C	I <sub>S</sub>	4.5 <sup>b, c</sup>		
Single Pulse Avalanche Current		I <sub>AS</sub>	30		
Single Pulse Avalanche Energy	L = 0.1 mH	E <sub>AS</sub>	45	mJ	
	T <sub>C</sub> = 25 °C		62.5		
Manianum Danier Disaination	T <sub>C</sub> = 70 °C		40	W	
Maximum Power Dissipation	T <sub>A</sub> = 25 °C	P <sub>D</sub>	5 <sup>b, c</sup>	VV	
	T <sub>A</sub> = 70 °C		3.2 <sup>b, c</sup>		
Operating Junction and Storage Temperature Range		T <sub>J</sub> , T <sub>stg</sub>	- 55 to 150	°C	
Soldering Recommendations (Peak Temperature)d, e			260		

THERMAL RESISTANCE RATINGS					
Parameter		Symbol	Typical	Maximum	Unit
Maximum Junction-to-Ambient <sup>b, f</sup>	t ≤ 10 s	R <sub>thJA</sub>	20	25	°C/W
Maximum Junction-to-Case (Drain)	Steady State	$R_{thJC}$	1.5	2.0	C/VV

#### **Notes**

- a. Package limited.
- b. Surface mounted on 1" x 1" FR4 board.
- c. t = 10 s
- d. The TO-220 is a leadless package. The end of the lead terminal is exposed copper (not plated) as a result of the singulation process in manufacturing. A solder fillet at the exposed copper tip cannot be guaranteed and is not required to ensure adequate bottom side solder interconnection.
- e. Rework conditions: manual soldering with a soldering iron is not recommended for leadless components.
- f. Maximum under steady state conditions is 70 °C/W.



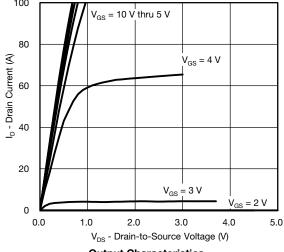
Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit	
Static				<u> </u>			
Drain-Source Breakdown Voltage	V <sub>DS</sub>	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$	80			V	
V <sub>DS</sub> Temperature Coefficient	$\Delta V_{DS}/T_{J}$			37		14/00	
V <sub>GS(th)</sub> Temperature Coefficient	$\Delta V_{GS(th)}/T_J$	$I_D = 250 \mu A$		- 6.1		mV/°C	
Gate-Source Threshold Voltage	V <sub>GS(th</sub> )	$V_{DS} = V_{GS}, I_D = 250 \mu A$	1.4		2.6	V	
Gate-Source Leakage	I <sub>GSS</sub>	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 20 \text{ V}$			± 100	nA	
Zaura Carta Valta via Duniu Communi		$V_{DS} = 80 \text{ V}, V_{GS} = 0 \text{ V}$			1	_	
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	V <sub>DS</sub> = 80 V, V <sub>GS</sub> = 0 V, T <sub>J</sub> = 55 °C			10	μA	
On-State Drain Current <sup>a</sup>	I <sub>D(on)</sub>	$V_{DS} \ge 5 \text{ V}, V_{GS} = 10 \text{ V}$	30			Α	
		$V_{GS} = 10 \text{ V}, I_D = 20 \text{ A}$		0.0064			
Drain-Source On-State Resistance <sup>a</sup>	R <sub>DS(on)</sub>	V <sub>GS</sub> = 6 V, I <sub>D</sub> = 15 A		0.0070		Ω	
	, ,	$V_{GS} = 4.5 \text{ V}, I_D = 10 \text{ A}$		0.0087		1	
Forward Transconductancea	9 <sub>fs</sub>	$V_{DS} = 10 \text{ V}, I_{D} = 20 \text{ A}$		60		S	
Dynamic <sup>b</sup>							
ut Capacitance C <sub>iss</sub>			1855				
Output Capacitance	C <sub>oss</sub>	$V_{DS} = 40 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHz}$		950		pF	
Reverse Transfer Capacitance	C <sub>rss</sub>			76			
		$V_{DS} = 40 \text{ V}, V_{GS} = 10 \text{ V}, I_D = 10 \text{ A}$		35.5	54	nC	
Total Gate Charge	$Q_g$	V <sub>DS</sub> = 40 V, V <sub>GS</sub> = 6 V, I <sub>D</sub> = 10 A		22	33		
				17.1	26		
Gate-Source Charge	$Q_{gs}$	$V_{DS} = 40 \text{ V}, V_{GS} = 4.5 \text{ V}, I_D = 10 \text{ A}$		5.3			
Gate-Drain Charge	$Q_{gd}$			7.3			
Output Charge	Q <sub>oss</sub>	$V_{DS} = 40 \text{ V}, V_{GS} = 0 \text{ V}$		57	86		
Gate Resistance	$R_g$	f = 1 MHz	0.5	1.3	2	Ω	
Turn-On Delay Time	t <sub>d(on)</sub>			12	24		
Rise Time	t <sub>r</sub>	$V_{DD} = 40 \text{ V}, R_L = 4 \Omega$		8	16		
Turn-Off DelayTime	t <sub>d(off)</sub>	$I_D \cong 10 \text{ A}, V_{GEN} = 10 \text{ V}, R_g = 1 \Omega$		32	64		
Fall Time	t <sub>f</sub>			7	14	no	
Turn-On Delay Time	t <sub>d(on)</sub>			14	28	ns	
Rise Time	t <sub>r</sub>	$V_{DD} = 40 \text{ V}, R_L = 4 \Omega$		11	22		
Turn-Off DelayTime	t <sub>d(off)</sub>	$I_D\cong\ 10\ A,\ V_{GEN}=6.0\ V,\ R_g=1\ \Omega$		30	60	]	
Fall Time	t <sub>f</sub>			8	16		
<b>Drain-Source Body Diode Characteristic</b>	s						
Continuous Source-Drain Diode Current	I <sub>S</sub>	T <sub>C</sub> = 25 °C			75	А	
Pulse Diode Forward Current (t = 100 $\mu$ s)	I <sub>SM</sub>				150	^	
Body Diode Voltage	$V_{SD}$	I <sub>S</sub> = 5 A		0.76	1.1	V	
Body Diode Reverse Recovery Time	t <sub>rr</sub>			38	75	ns	
Body Diode Reverse Recovery Charge	Q <sub>rr</sub>	In = 10 A dI/dt = 100 A/up Tr = 25 °C		36	70	nC	
Reverse Recovery Fall Time	ta	I <sub>F</sub> = 10 A, dl/dt = 100 A/μs, T <sub>J</sub> = 25 °C		19		ne	
Reverse Recovery Rise Time	t <sub>b</sub>			19		ns	

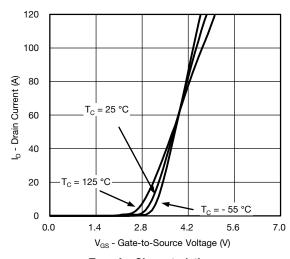
#### Notes

- a. Pulse test; pulse width  $\leq 300~\mu s,~duty~cycle \leq 2~\%.$
- b. Guaranteed by design, not subject to production testing.

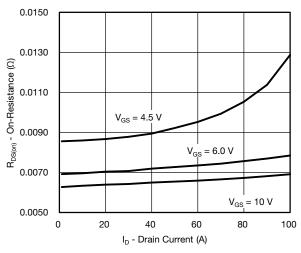
Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.



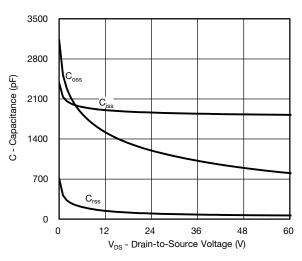




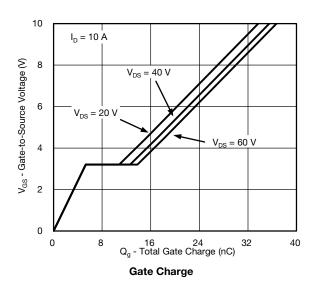




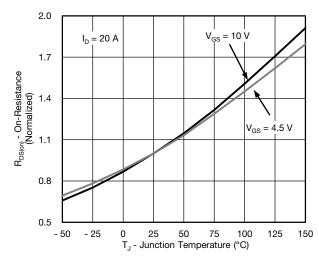




#### On-Resistance vs. Drain Current

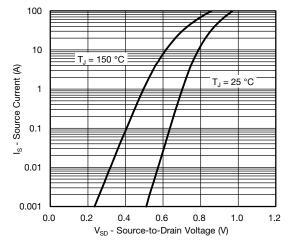


Capacitance

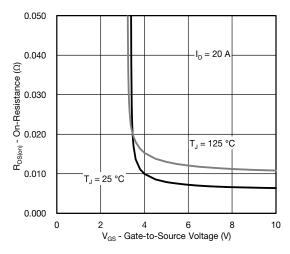


On-Resistance vs. Junction Temperature

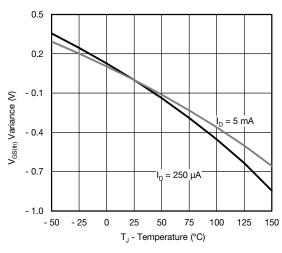




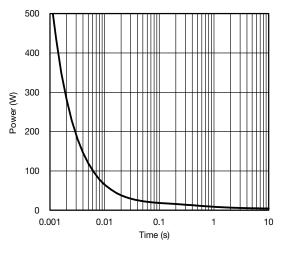
Source-Drain Diode Forward Voltage



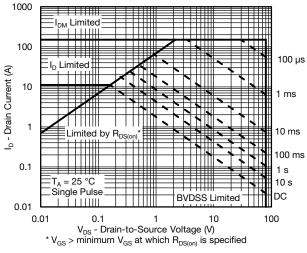
On-Resistance vs. Gate-to-Source Voltage



**Threshold Voltage** 

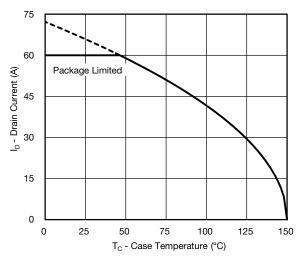


Single Pulse Power, Junction-to-Ambient

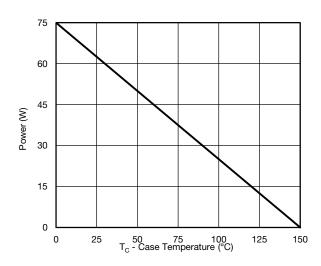


Safe Operating Area, Junction-to-Ambient

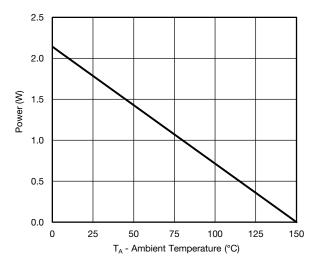




#### **Current Derating\***



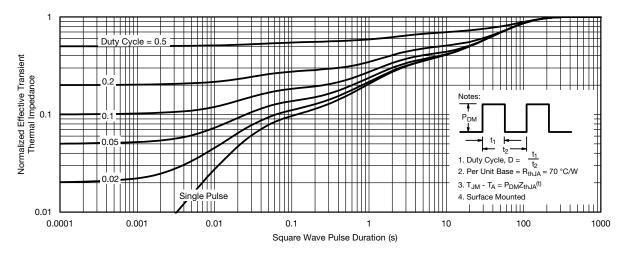




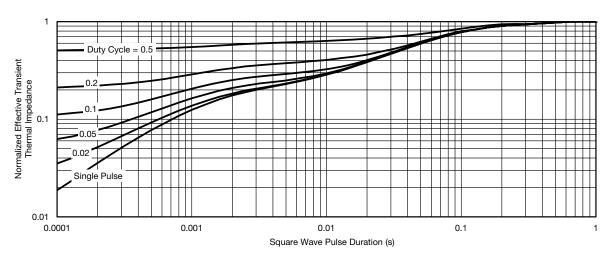
Power, Junction-to-Ambient

<sup>\*</sup> The power dissipation  $P_D$  is based on  $T_{J(max.)} = 150$  °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.





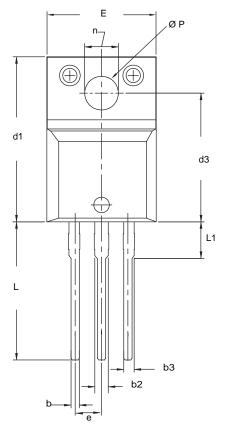
Normalized Thermal Transient Impedance, Junction-to-Ambient

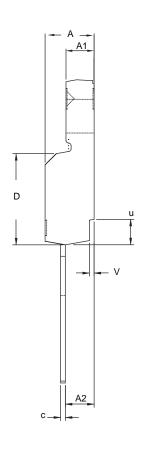


Normalized Thermal Transient Impedance, Junction-to-Case



### **TO-220 FULLPAK (HIGH VOLTAGE)**





DIM.	MILLIMETERS		INCHES	
	MIN.	MAX.	MIN.	MAX.
Α	4.570	4.830	0.180	0.190
A1	2.570	2.830	0.101	0.111
A2	2.510	2.850	0.099	0.112
b	0.622	0.890	0.024	0.035
b2	1.229	1.400	0.048	0.055
b3	1.229	1.400	0.048	0.055
С	0.440	0.629	0.017	0.025
D	8.650	9.800	0.341	0.386
d1	15.88	16.120	0.622	0.635
d3	12.300	12.920	0.484	0.509
E	10.360	10.630	0.408	0.419
е	2.54	BSC	0.100	BSC
L	13.200	13.730	0.520	0.541
L1	3.100	3.500	0.122	0.138
n	6.050	6.150	0.238	0.242
ØΡ	3.050	3.450	0.120	0.136
u	2.400	2.500	0.094	0.098
V	0.400	0.500	0.016	0.020

ECN: X09-0126-Rev. B, 26-Oct-09 DWG: 5972

- To be used only for process drawing.
  These dimensions apply to all TO-220, FULLPAK leadframe versions 3 leads.
  All critical dimensions should C meet C<sub>pk</sub> > 1.33.
  All dimensions include burrs and plating thickness.
  No chipping or package damage.

服务热线:400-655-8788



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